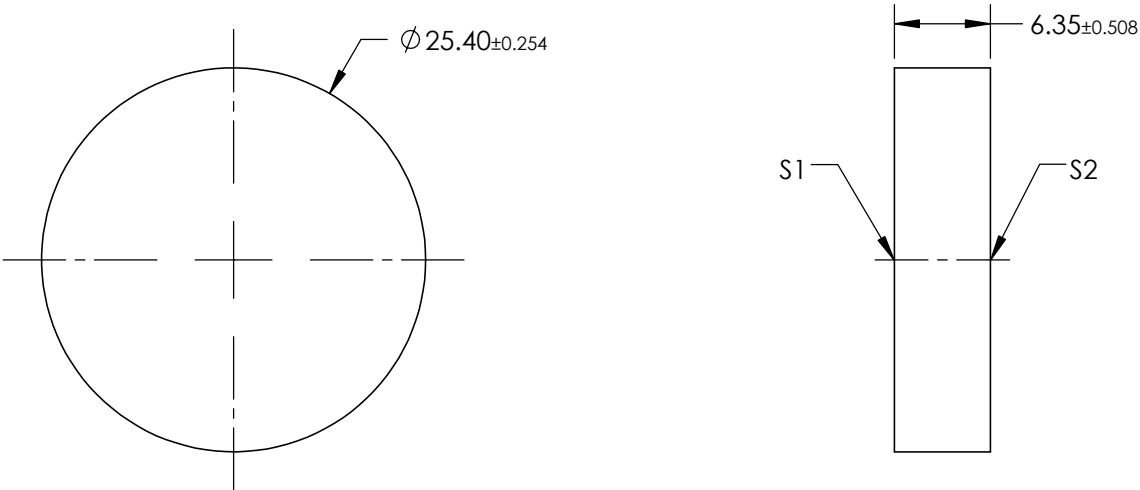


- NOTES:
- 1. SUBSTRATE:
SINGLE CRYSTAL SILICON
 - 2. COATING (APPLY ACROSS COATING APERTURE):
Mo/Si MULTILAYER; TOP LAYER Si


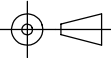
S1: R(ABS) > 65% (S-POLARIZATION) @ 13.5nm; FWHM 0.98nm
S2: NONE
 - 3. WAVELENGTH RANGE (nm): 12.92 - 13.90

**FOR INFORMATION ONLY:
DO NOT MANUFACTURE
PARTS TO THIS DRAWING**



SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

	S1	S2
SHAPE	PLANO	PLANO
SURFACE ROUGHNESS	< 3 Å RMS	N/A
SURFACE FLATNESS	λ/10	N/A
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

 Edmund Optics®			
THIRD ANGLE PROJECTION 		TITLE	13.5nm, 25.4mm DIA, 45° AOI, EUV FLAT MIRROR
ALL DIMS IN	mm	DWG NO	38760
			SHEET 1 OF 1